

## AOT430

### N-Channel Enhancement Mode Field Effect Transistor

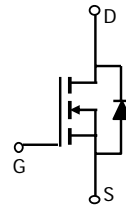
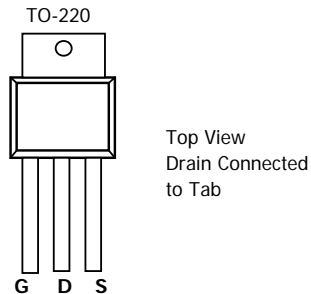
#### General Description

The AOT430 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications. *Standard Product AOT430 is Pb-free (meets ROHS & Sony 259 specifications).*

#### Features

$V_{DS} (V) = 75V$   
 $I_D = 80 A$  ( $V_{GS} = 10V$ )  
 $R_{DS(ON)} < 11.5m\Omega$  ( $V_{GS} = 10V$ )

**UIS TESTED!**



#### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	75	V
Gate-Source Voltage	$V_{GS}$	$\pm 25$	V
Continuous Drain Current	$I_D$	$T_C=25^\circ C^G$	80
		$T_C=100^\circ C$	78
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	200	A
Avalanche Current <sup>C</sup>	$I_{AR}$	45	A
Repetitive avalanche energy $L=0.3mH^C$	$E_{AR}$	300	mJ
Power Dissipation <sup>B</sup>	$P_D$	$T_C=25^\circ C$	268
		$T_C=100^\circ C$	134
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 175	$^\circ C$

#### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	45	60	$^\circ C/W$
Steady-State				
Maximum Junction-to-Case <sup>B</sup>	$R_{\theta JC}$	0.45	0.56	$^\circ C/W$
Steady-State				

**Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	75			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			1 5	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±25V			1	μA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2	2.7	4	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> =10V, V <sub>DS</sub> =5V	200			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =30A T <sub>J</sub> =125°C		9.8 16.0	11.5 19.0	mΩ
g <sub>FS</sub>	Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =80A		90		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V		0.7	1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current <sup>G</sup>				80	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V, f=1MHz		4700		pF
C <sub>oss</sub>	Output Capacitance			400		pF
C <sub>riss</sub>	Reverse Transfer Capacitance			180		pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		3		Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g(10V)</sub>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =30V, I <sub>D</sub> =30A		114		nC
Q <sub>gs</sub>	Gate Source Charge			33		nC
Q <sub>gd</sub>	Gate Drain Charge			18		nC
t <sub>D(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> =10V, V <sub>DS</sub> =30V, R <sub>L</sub> =1Ω, R <sub>GEN</sub> =3Ω		21		ns
t <sub>r</sub>	Turn-On Rise Time			39		ns
t <sub>D(off)</sub>	Turn-Off DelayTime			70		ns
t <sub>f</sub>	Turn-Off Fall Time			24		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time		I <sub>F</sub> =30A, dI/dt=100A/μs		53	
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =30A, dI/dt=100A/μs		143		nC

A: The value of R<sub>θJA</sub> is measured with the device in a still air environment with T<sub>A</sub>=25°C.

B: The power dissipation P<sub>D</sub> is based on T<sub>J(MAX)</sub>=175°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=175°C.

D: The R<sub>θJA</sub> is the sum of the thermal impedance from junction to case R<sub>θJC</sub> and case to ambient.

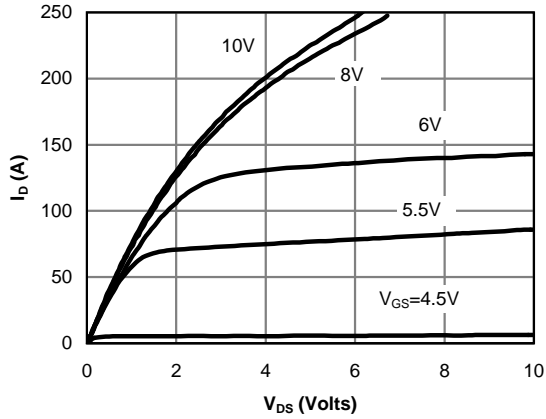
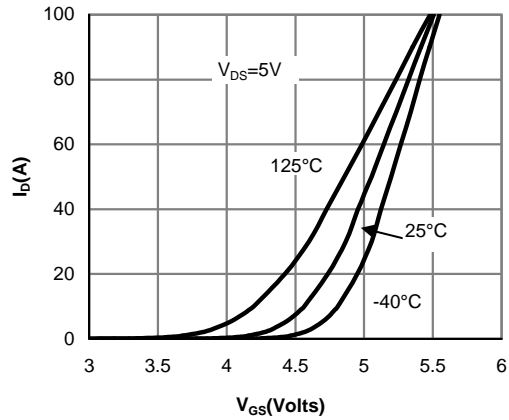
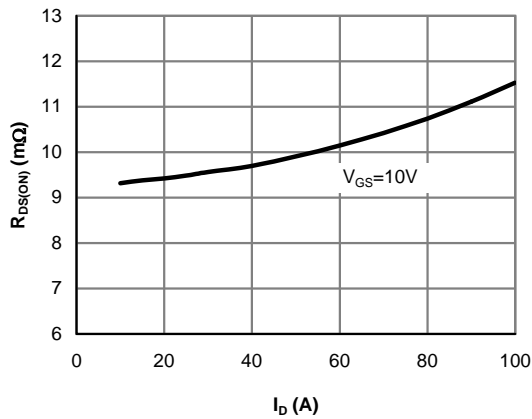
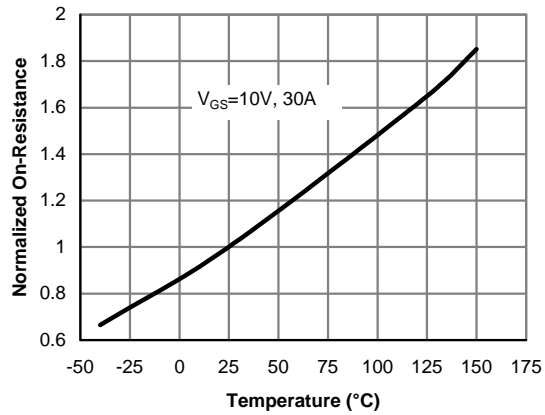
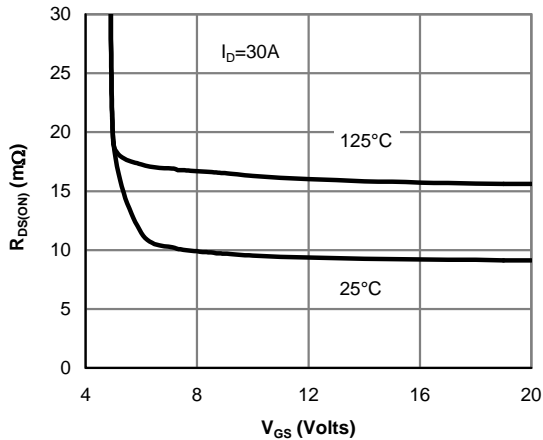
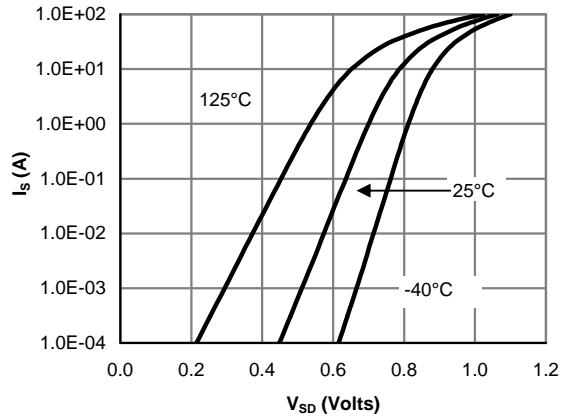
E: The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

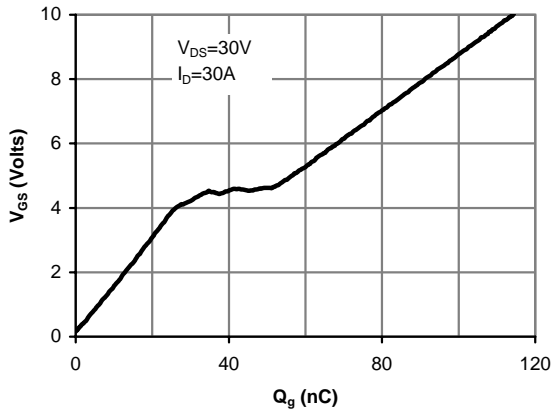
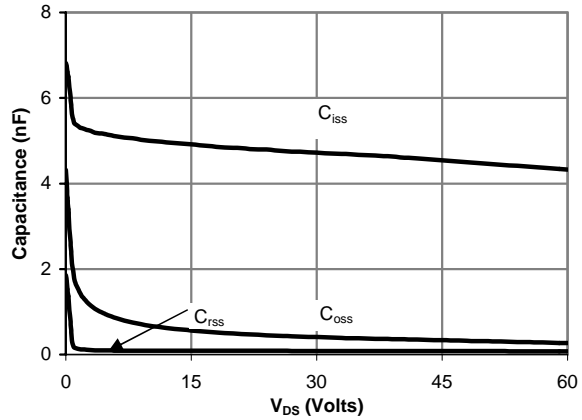
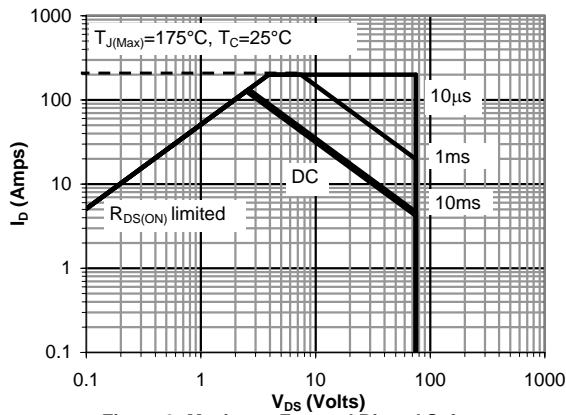
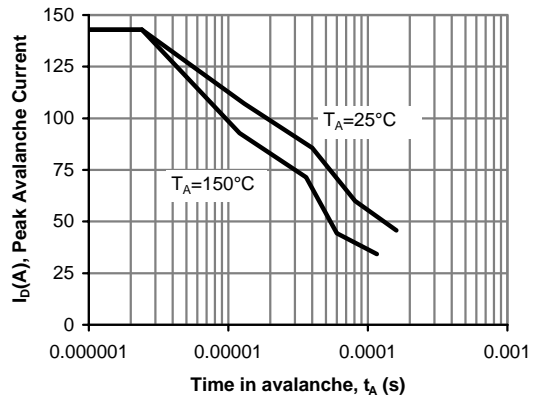
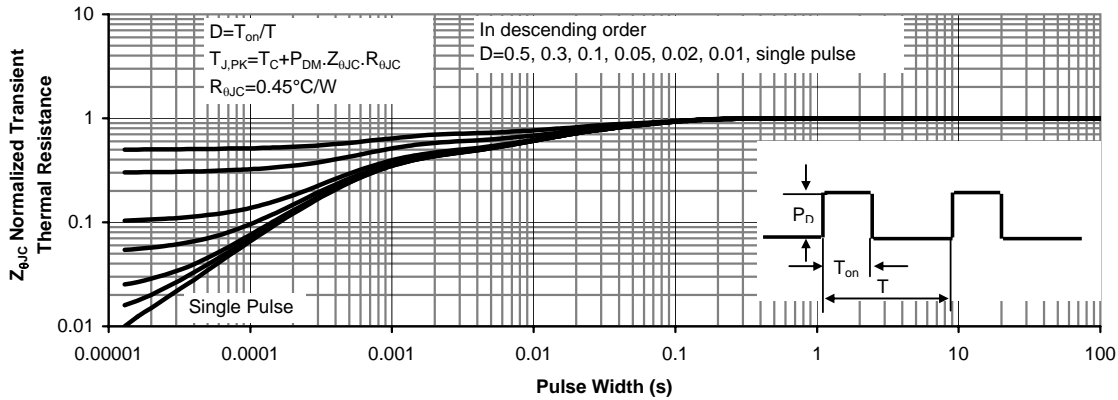
F: These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=175°C.

G: The maximum current rating is limited by bond-wires.

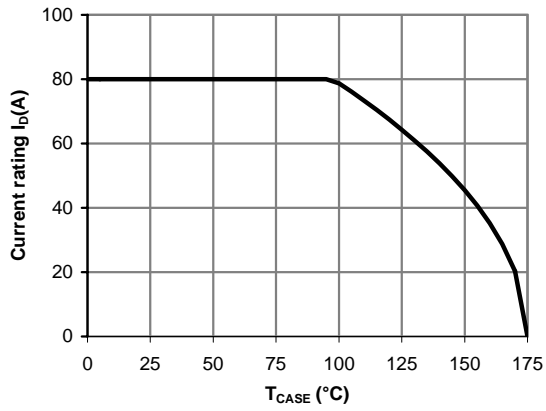
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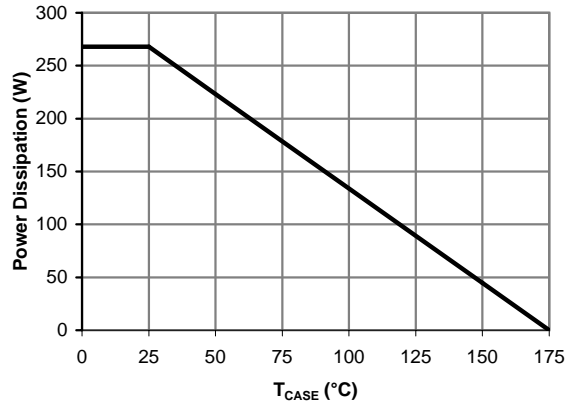
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 1: On-Region Characteristics**

**Figure 2: Transfer Characteristics**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**

**Figure 4: On-Resistance vs. Junction Temperature**

**Figure 5: On-Resistance vs. Gate-Source Voltage**

**Figure 6: Body-Diode Characteristics**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 10: Single Pulse Avalanche capability**

**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**



**Figure 12: Current De-rating (Note B)**



**Figure 13: Power De-rating (Note B)**